

Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

FUJITA ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
708	251, 254	8/1/2007	MAI

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	8/1/2007	MAI